



500.40120X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): T. OTSUBO, et al
Serial No.: 09/855,674
Filed: May 16, 2001
For: APPARATUS FOR MONITORING THICKNESS OF
DEPOSITED LAYER IN REACTOR AND DRY PROCESSING
METHOD
Group: 2877
Examiner: K. Brown

**PROPOSED AMENDMENT TO THE DRAWINGS
AND CORRECTED SUBSTITUTE DRAWINGS**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

September 22, 2003

Sir:

It is proposed that the drawings in the above-identified application be amended in accordance with the attached red-lined print and corrected drawings incorporating the changes are submitted herewith.

Respectfully submitted,

Melvin Kraus
Registration No. 22,466
ANTONELLI, TERRY, STOUT & KRAUS, LLP

MK/cee
Attachment(s)
(703) 312-6600

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